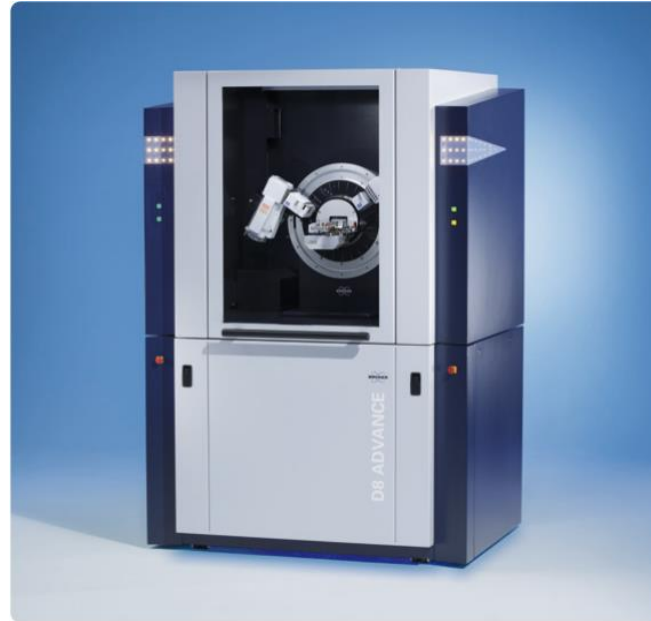




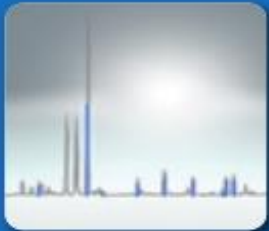
D8 ADVANCE

X-Ray Diffractometer (XRD)

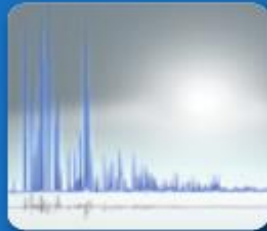
- High temperature XRD (upto 1600°C)
- Grazing Incidence XRD (GIXRD)
- Small Angle X-Ray Scattering (SAXS)
- X-Ray Reflectivity (XRR)
- Low Angle XRD
- Phase Identification/Quantification
- Structure Refinement
- Microstructure
- Indexing
- Fiber Orientation



Application



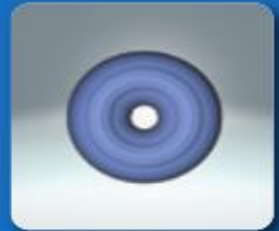
Qualitative & quantitative phase analysis



Structural analysis



X-Ray Reflectometry analysis



Small Angle X-Ray Scattering

Technical details

Max. usable angular range = $2\theta \leq 168^\circ$
Smallest addressable increment = 0.0001°
Max. angular speed = $20^\circ/s$
Non-Ambient Conditions (High Temperature)
Cu anode with 3kW Generator
Twin-Twin Optics (Motorized slit and Göbel Mirror)
LYNXEYE Family Detector (0D and 1D mode)

Contact:

Dr. H. Shankar
Materials Characterization Lab,
Centre for Research and Development,
KPR Institute of Engineering and Technology
Arasur, Coimbatore – 641407

Charges

External Users

Research Scholars / Students: Rs.450/-*
Industry: Rs. 900/-*
GI XRD Thin Films : Rs. 600/-*
High Temp. XRD Measurement: Rs. 5000/-*

*Charges vary based on conditions

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